

This Page Is Inserted by IFW Operations  
and is not a part of the Official Record

## **BEST AVAILABLE IMAGES**

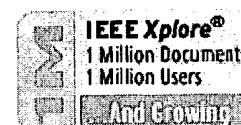
Defective images within this document are accurate representations of the original documents submitted by the applicant.

Defects in the images may include (but are not limited to):

- BLACK BORDERS
- TEXT CUT OFF AT TOP, BOTTOM OR SIDES
- FADED TEXT
- ILLEGIBLE TEXT
- SKEWED/SLANTED IMAGES
- COLORED PHOTOS
- BLACK OR VERY BLACK AND WHITE DARK PHOTOS
- GRAY SCALE DOCUMENTS

## **IMAGES ARE BEST AVAILABLE COPY.**

**As rescanning documents *will not* correct images,  
please do not report the images to the  
Image Problem Mailbox.**

[IEEE HOME](#) | [SEARCH IEEE](#) | [SHOP](#) | [WEB ACCOUNT](#) | [CONTACT IEEE](#)[Membership](#) | [Publications/Services](#) | [Standards](#) | [Conferences](#) | [Careers/Jobs](#)**IEEE Xplore®**  
RELEASE 1.7[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)[Quick Links](#)>> [See](#)**Welcome to IEEE Xplore®**

- ☐ [Home](#)
- ☐ [What Can I Access?](#)
- ☐ [Log-out](#)

**Tables of Contents**

- ☐ [Journals & Magazines](#)
- ☐ [Conference Proceedings](#)
- ☐ [Standards](#)

**Search**

- ☐ [By Author](#)
- ☐ [Basic](#)
- ☐ [Advanced](#)

**Member Services**

- ☐ [Join IEEE](#)
- ☐ [Establish IEEE Web Account](#)
- ☐ [Access the IEEE Member Digital Library](#)

**IEEE Enterprise**

- ☐ [Access the IEEE Enterprise File Cabinet](#)

Your search matched **0** of **1051129** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.**Refine This Search:**

You may refine your search by editing the current search expression or enter a new one in the text box.

☐ Check to search within this result set**Results Key:****JNL** = Journal or Magazine   **CNF** = Conference   **STD** = Standard

= Your access to full-text

**Results:****No documents matched your query.** **Print Format**

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

[IEEE HOME](#) | [SEARCH IEEE](#) | [SHOP](#) | [WEB ACCOUNT](#) | [CONTACT IEEE](#)[Membership](#) | [Publications/Services](#) | [Standards](#) | [Conferences](#) | [Careers/Jobs](#)**IEEE Xplore®**  
RELEASE 1.7» [See](#)[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)[Quick Links](#)**Welcome to IEEE Xplore®**

- ☐ [Home](#)
- ☐ [What Can I Access?](#)
- ☐ [Log-out](#)

**Tables of Contents**

- ☐ [Journals & Magazines](#)
- ☐ [Conference Proceedings](#)
- ☐ [Standards](#)

**Search**

- ☐ [By Author](#)
- ☐ [Basic](#)
- ☐ [Advanced](#)

**Member Services**

- ☐ [Join IEEE](#)
- ☐ [Establish IEEE Web Account](#)
- ☐ [Access the IEEE Member Digital Library](#)

**IEEE Enterprise**

- ☐ [Access the IEEE Enterprise File Cabinet](#)



[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Your search matched **0** of **1051129** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.**Refine This Search:**

You may refine your search by editing the current search expression or enter a new one in the text box.

☐ Check to search within this result set**Results Key:****JNL** = Journal or Magazine   **CNF** = Conference   **STD** = Standard

= Your access to full-text

**Results:****No documents matched your query.**

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership Publications/Services Standards Conferences Careers/Jobs

**IEEE Xplore®**  
 RELEASE 1.7

[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)
[Quick Links](#)
» [See](#)**Welcome to IEEE Xplore®**

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

**Tables of Contents**

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

**Search**

- ☐ By Author
- ☐ Basic
- ☐ Advanced

**Member Services**

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

**IEEE Enterprise**

- ☐ Access the IEEE Enterprise File Cabinet

**Print Format**

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

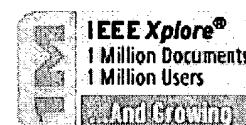
Your search matched **0** of **1051129** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.**Refine This Search:**

You may refine your search by editing the current search expression or enter a new one in the text box.


☐ Check to search within this result set
**Results Key:****JNL** = Journal or Magazine   **CNF** = Conference   **STD** = Standard

= Your access to full-text

**Results:****No documents matched your query.**

[IEEE HOME](#) | [SEARCH IEEE](#) | [SHOP](#) | [WEB ACCOUNT](#) | [CONTACT IEEE](#)[Membership](#) | [Publications/Services](#) | [Standards](#) | [Conferences](#) | [Careers/Jobs](#)**IEEE Xplore®**  
RELEASE 1.7[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)[Quick Links](#)» [See](#)**Welcome to IEEE Xplore®**

- ☐ [Home](#)
- ☐ [What Can I Access?](#)
- ☐ [Log-out](#)

**Tables of Contents**

- ☐ [Journals & Magazines](#)
- ☐ [Conference Proceedings](#)
- ☐ [Standards](#)

**Search**

- ☐ [By Author](#)
- ☐ [Basic](#)
- ☐ [Advanced](#)

**Member Services**

- ☐ [Join IEEE](#)
- ☐ [Establish IEEE Web Account](#)
- ☐ [Access the IEEE Member Digital Library](#)

**IEEE Enterprise**

- ☐ [Access the IEEE Enterprise File Cabinet](#)

[Print Format](#)Your search matched **0** of **1051129** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.**Refine This Search:**

You may refine your search by editing the current search expression or enter a new one in the text box.

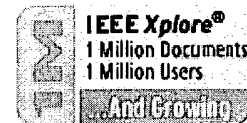
☐ Check to search within this result set**Results Key:****JNL** = Journal or Magazine   **CNF** = Conference   **STD** = Standard

= Your access to full-text

**Results:****No documents matched your query.**

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

[IEEE HOME](#) | [SEARCH IEEE](#) | [SHOP](#) | [WEB ACCOUNT](#) | [CONTACT IEEE](#)[Membership](#) | [Publications/Services](#) | [Standards](#) | [Conferences](#) | [Careers/Jobs](#)**IEEE Xplore®**  
RELEASE 1.7[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)[Quick Links](#)>> [See](#)**Welcome to IEEE Xplore®**

- ☐ [Home](#)
- ☐ [What Can I Access?](#)
- ☐ [Log-out](#)

**Tables of Contents**

- ☐ [Journals & Magazines](#)
- ☐ [Conference Proceedings](#)
- ☐ [Standards](#)

**Search**

- ☐ [By Author](#)
- ☐ [Basic](#)
- ☐ [Advanced](#)

**Member Services**

- ☐ [Join IEEE](#)
- ☐ [Establish IEEE Web Account](#)
- ☐ [Access the IEEE Member Digital Library](#)

**IEEE Enterprise**

- ☐ [Access the IEEE Enterprise File Cabinet](#)

Your search matched **0** of **1051129** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.**Refine This Search:**

You may refine your search by editing the current search expression or enter a new one in the text box.

☐ Check to search within this result set**Results Key:****JNL** = Journal or Magazine   **CNF** = Conference   **STD** = Standard

= Your access to full-text

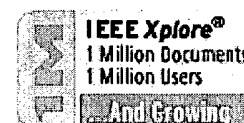
**Results:****No documents matched your query.** [Print Format](#)[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership Publications/Services Standards Conferences Careers/Jobs

**IEEE Xplore®**  
 RELEASE 1.7


&gt;&gt; See

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)
[Quick Links](#)

## Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

## Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

## Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced

## Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

## IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Print Format

Your search matched **2** of **1051129** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

## Refine This Search:

You may refine your search by editing the current search expression or enter a new one in the text box.


☐ Check to search within this result set

## Results Key:

**JNL** = Journal or Magazine    **CNF** = Conference    **STD** = Standard

= Your access to full-text

1 **A thermal-aware superscalar microprocessor**

Chee How Lim; Daasch, W.R.; Cai, G.;

Quality Electronic Design, 2002. Proceedings. International Symposium on , 1 March 2002

Pages:517 - 522

[\[Abstract\]](#)
[\[PDF Full-Text \(248 KB\)\]](#)

IEEE CNF

2 **NwsAlarm: a tool for accurately detecting resource performance degradation**

Krintz, C.; Wolski, R.;

Cluster Computing and the Grid, 2001. Proceedings. First IEEE/ACM International Symposium on , 15-18 May 2001

Pages:404 - 413

[\[Abstract\]](#)
[\[PDF Full-Text \(880 KB\)\]](#)

IEEE CNF

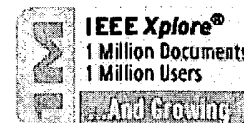
[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership Publications/Services Standards Conferences Careers/Jobs

**IEEE Xplore®**  
 RELEASE 1.7


&gt;&gt; See

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)
[Quick Links](#)

## Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

## Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

## Search

- ☐ By Author
- ☐ Basic
- ☒ Advanced

## Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

## IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Print Format

Your search matched **7** of **1051129** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.**Refine This Search:**

You may refine your search by editing the current search expression or enter a new one in the text box.

email&lt;and&gt;overload

Search

☐ Check to search within this result set**Results Key:****JNL** = Journal or Magazine **CNF** = Conference **STD** = Standard

= Your access to full-text

**1 I have seen the future: it is flooded with email***Reisman, S.;*

Software, IEEE , Volume: 12 , Issue: 3 , May 1995

Pages:111 - 112

[\[Abstract\]](#) [\[PDF Full-Text \(196 KB\)\]](#) **IEEE JNL**
**2 An automated system for distributing literature and managing information overload***Stoffel, A.W.;*

Aerospace Conference Proceedings, 2002. IEEE , Volume: 7 , 9-16 March 200

Pages:7-3321 - 7-3326 vol.7

[\[Abstract\]](#) [\[PDF Full-Text \(506 KB\)\]](#) **IEEE CNF**
**3 Persistence and lurkers in discussion lists: a pilot study***Nonnecke, B.; Preece, J.;*

System Sciences, 2000. Proceedings of the 33rd Annual Hawaii International Conference on , 4-7 Jan. 2000

Pages:10 pp.

[\[Abstract\]](#) [\[PDF Full-Text \(88 KB\)\]](#) **IEEE CNF**
**4 Senddata: an agent for data processing systems using email***Kwak, J.D.; Elmasri, R.; Lee, K.K.;*

Performance, Computing, and Communications Conference, 2000. IPCCC '00. Conference Proceeding of the IEEE International , 20-22 Feb. 2000

Pages:264 - 270



[\[Abstract\]](#)   [\[PDF Full-Text \(588 KB\)\]](#)   IEEE CNF

---

**5 ADTP: a new protocol for data processing over the internet**

*Kwak, J.D.; Elmasri, R.; Wook Choi; Rung-Chi Ye; Mahareddy, A.;*

Database and Expert Systems Applications, 2001. Proceedings. 12th International Workshop on , 3-7 Sept. 2001

Pages:222 - 226

[\[Abstract\]](#)   [\[PDF Full-Text \(320 KB\)\]](#)   IEEE CNF

---

**6 Dynamic email organization via relevance categories**

*Mock, K.;*

Tools with Artificial Intelligence, 1999. Proceedings. 11th IEEE International Conference on , 9-11 Nov. 1999

Pages:399 - 405

[\[Abstract\]](#)   [\[PDF Full-Text \(56 KB\)\]](#)   IEEE CNF

---

**7 A management paradigm to reduce information overload-the introduction of the intranet into BT**

*Ireland, P.S.;*

IT Strategies for Information Overload (Digest No: 1997/340), IEE Colloquium on , 3 Dec. 1997

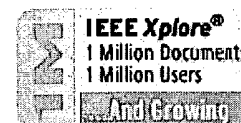
Pages:2/1 - 2/6

[\[Abstract\]](#)   [\[PDF Full-Text \(320 KB\)\]](#)   IEEE CNF

---

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

[IEEE HOME](#) | [SEARCH IEEE](#) | [SHOP](#) | [WEB ACCOUNT](#) | [CONTACT IEEE](#)[Membership](#) | [Publications/Services](#) | [Standards](#) | [Conferences](#) | [Careers/Jobs](#)**IEEE Xplore®**  
RELEASE 1.7[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)[Quick Links](#)>> [See](#)**Welcome to IEEE Xplore®**

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

**Tables of Contents**

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

**Search**

- ☐ By Author
- ☐ Basic
- ☐ Advanced

**Member Services**

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

**IEEE Enterprise**

- ☐ Access the IEEE Enterprise File Cabinet

**Print Format**

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

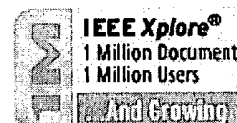
Your search matched **0** of **1051129** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.**Refine This Search:**

You may refine your search by editing the current search expression or enter a new one in the text box.

☐ Check to search within this result set**Results Key:****JNL** = Journal or Magazine   **CNF** = Conference   **STD** = Standard

= Your access to full-text

**Results:****No documents matched your query.**

[IEEE HOME](#) | [SEARCH IEEE](#) | [SHOP](#) | [WEB ACCOUNT](#) | [CONTACT IEEE](#)[Membership](#) | [Publications/Services](#) | [Standards](#) | [Conferences](#) | [Careers/Jobs](#)**IEEE Xplore®**  
RELEASE 1.7[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)[Quick Links](#)

&gt;&gt; See

**Welcome to IEEE Xplore®**

- ☐ [Home](#)
- ☐ [What Can I Access?](#)
- ☐ [Log-out](#)

**Tables of Contents**

- ☐ [Journals & Magazines](#)
- ☐ [Conference Proceedings](#)
- ☐ [Standards](#)

**Search**

- ☐ [By Author](#)
- ☐ [Basic](#)
- ☐ [Advanced](#)

**Member Services**

- ☐ [Join IEEE](#)
- ☐ [Establish IEEE Web Account](#)
- ☐ [Access the IEEE Member Digital Library](#)

**IEEE Enterprise**

- ☐ [Access the IEEE Enterprise File Cabinet](#)

Your search matched **0** of **1051129** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.**Refine This Search:**

You may refine your search by editing the current search expression or enter a new one in the text box.

☐ Check to search within this result set**Results Key:****JNL** = Journal or Magazine   **CNF** = Conference   **STD** = Standard

= Your access to full-text

**Results:****No documents matched your query.** **Print Format**

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

[IEEE HOME](#) | [SEARCH IEEE](#) | [SHOP](#) | [WEB ACCOUNT](#) | [CONTACT IEEE](#)[Membership](#) | [Publications/Services](#) | [Standards](#) | [Conferences](#) | [Careers/Jobs](#)**IEEE Xplore®**  
RELEASE 1.7[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)[Quick Links](#)

» See

**Welcome to IEEE Xplore®**

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

**Tables of Contents**

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

**Search**

- ☐ By Author
- ☐ Basic
- ☐ Advanced

**Member Services**

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

**IEEE Enterprise**

- ☐ Access the IEEE Enterprise File Cabinet

[Print Format](#)Your search matched **3** of **1051129** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.**Refine This Search:**

You may refine your search by editing the current search expression or enter a new one in the text box.

☐ Check to search within this result set**Results Key:****JNL** = Journal or Magazine   **CNF** = Conference   **STD** = Standard

= Your access to full-text

**1 I have seen the future: it is flooded with email***Reisman, S.;*

Software, IEEE , Volume: 12 , Issue: 3 , May 1995

Pages:111 - 112

[\[Abstract\]](#)   [\[PDF Full-Text \(196 KB\)\]](#)   **IEEE JNL****2 Persistence and lurkers in discussion lists: a pilot study***Nonnecke, B.; Preece, J.;*

System Sciences, 2000. Proceedings of the 33rd Annual Hawaii International Conference on , 4-7 Jan. 2000

Pages:10 pp.

[\[Abstract\]](#)   [\[PDF Full-Text \(88 KB\)\]](#)   **IEEE CNF****3 New strategy and techniques to cope with information overload***Etzel, B.;*

Information Overload, IEE Colloquium on , 20 Nov 1995

Pages:2/1 - 210

[\[Abstract\]](#)   [\[PDF Full-Text \(552 KB\)\]](#)   **IEE CNF**[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved